ABSTRACT

TEST DEVICE AND TEST METHOD THEREOF

Embodiments of the present invention disclose a test device. The test device includes a rack, a transfer tray, a transfer module, and a flip module holding a test carrier. The transfer module and the flip module are arranged on the rack. The transfer tray is placed on the rack. The rack has a first region and a second region. When the transfer tray is located in the first region, the transfer module transfers the transfer tray to the second region. The flip module holds the transfer tray, presses the transfer tray and the test carrier to each other, and flips the transfer tray and the test carrier whereby multiple untested chips carried by the transfer tray are ~~all~~ mutually transferred to the test carrier. The multiple untested chips on the transfer tray are transferred to the test carrier while pins of the chips face upwards, multiple chips can be automatically flipped at one time, and test efficiency can be improved.

Figure 1